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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
NL	6,092,224	7/2000	LeBlanc et al.	—		
↓	5,949,797	9/1999	Jung	—		
	5,838,692	11/1998	Tobin	—		
	5,799,021	8/1998	Gheewala	—		
	5,578,938	11/1996	Kazami	—		
	5,235,566	8/1993	Merrill	—		
	5,231,314	7/1993	Andrews	—		
	5,208,178	5/1993	Usami	—		
↓	5,369,643	11/1994	Rastgar et al.	—		
NL	6,038,691	3/2000	Nakao et al.	—		

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

NL		Nakao et al., LOW OVERHEAD TEST POINT INSERTION FOR SCAN-BASED BIST, ITC International Test Conference, pages 348-357.
NL		M. Youssef et al., Methodology for Efficiently Inserting and Condensing Test Points, IEEE Proceedings, pages 154-160, May 1993.

EXAMINER

*Nam*

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06/10/04

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.